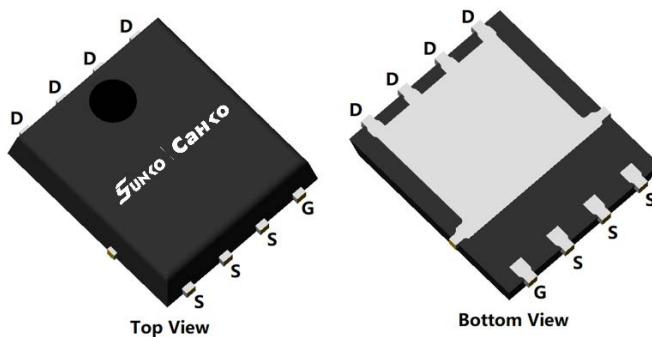
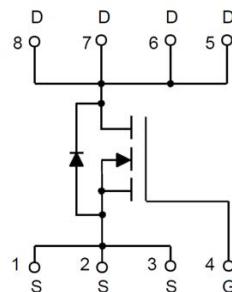


N-Channel Enhancement Mode Field Effect Transistor



PDFN5060-8L



Product Summary

- V_{DS} 60V
- I_D 95A
- $R_{DS(ON)}$ (at $V_{GS}=10V$) <2.9 mohm
- 100% EAS Tested
- 100% ∇V_{DS} Tested

General Description

- Split Gate Trench MOSFET technology
- Excellent package for heat dissipation
- High density cell design for low $R_{DS(ON)}$
- Moisture Sensitivity Level 1
- Epoxy Meets UL 94 V-0 Flammability Rating
- Halogen Free

Applications

- DC-DC Converters
- Power management functions
- Synchronous-rectification applications

Absolute Maximum Ratings ($T_A=25^\circ C$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-source Voltage	V_{DS}	60	V
Gate-source Voltage	V_{GS}	± 20	V
Drain Current (Silicon limited)	I_D	155	A
Drain Current ^A	$T_A=25^\circ C$	20	A
	$T_A=100^\circ C$	12	
	$T_c=25^\circ C$	95	
	$T_c=100^\circ C$	60	
Pulsed Drain Current ^B	I_{DM}	390	A
Avalanche energy ^C	EAS	800	mJ
Total Power Dissipation ^D	P_D	120	W
Thermal Resistance Junction-to-Case	$R_{\theta JC}$	1.04	$^\circ C/W$
Thermal Resistance Junction-to-Ambient ^E	$R_{\theta JA}$	20	
Junction and Storage Temperature Range	T_J, T_{STG}	-55~+150	$^\circ C$

Ordering Information (Example)

PREFERRED P/N	PACKING CODE	Marking	MINIMUM PACKAGE(pcs)	INNER BOX QUANTITY(pcs)	OUTER CARTON QUANTITY(pcs)	DELIVERY MODE
SCG95G06B	F1	SCG95G06B	5000	10000	100000	13" reel

■ Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Static Parameter						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	60			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}}=60\text{V}, V_{\text{GS}}=0\text{V}$			1	μA
Gate-Body Leakage Current	I_{GSS}	$V_{\text{GS}}= \pm 20\text{V}, V_{\text{DS}}=0\text{V}$			± 100	nA
Gate Threshold Voltage	$V_{\text{GS(th)}}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	2.0	2.8	4.0	V
Static Drain-Source On-Resistance	$R_{\text{DS(ON)}}$	$V_{\text{GS}}= 10\text{V}, I_{\text{D}}=20\text{A}$		2.25	2.9	$\text{m}\Omega$
Diode Forward Voltage	V_{SD}	$I_{\text{S}}=20\text{A}, V_{\text{GS}}=0\text{V}$			1.2	V
Maximum Body-Diode Continuous Current	I_{S}				95	A
Dynamic Parameters						
Input Capacitance	C_{iss}	$V_{\text{DS}}=25\text{V}, V_{\text{GS}}=0\text{V}, f=100\text{KHZ}$		5950		pF
Output Capacitance	C_{oss}			1250		
Reverse Transfer Capacitance	C_{rss}			85		
Switching Parameters						
Total Gate Charge	Q_g	$V_{\text{GS}}=10\text{V}, V_{\text{DS}}=50\text{V}, I_{\text{D}}=50\text{A}$		93		nC
Gate-Source Charge	Q_{gs}			17		
Gate-Drain Charge	Q_{gd}			14		
Reverse Recovery Charge	Q_{rr}	$I_{\text{F}}=25\text{A}, dI/dt=100\text{A/us}$		73		ns
Reverse Recovery Time	t_{rr}			68		
Turn-on Delay Time	$t_{\text{d(on)}}$	$V_{\text{GS}}=10\text{V}, V_{\text{DD}}=30\text{V}, I_{\text{D}}=25\text{A}$ $R_{\text{GEN}}=2\Omega$		22.5		
Turn-on Rise Time	t_r			6.7		
Turn-off Delay Time	$t_{\text{d(off)}}$			80.3		
Turn-off fall Time	t_f			26.9		

Note:

- A. The maximum current rating is package limited.
- B. Repetitive rating; pulse width limited by max. junction temperature.
- C. $T_J=25^\circ\text{C}, V_{\text{DD}}=55\text{V}, V_G=10\text{V}, R_G=25\Omega, L=4\text{mH}, I_{\text{AS}}=20\text{A}$.
- D. P_D is based on max. junction temperature, using junction-case thermal resistance.
- E. The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_a=25^\circ\text{C}$.

■ Typical Performance Characteristics

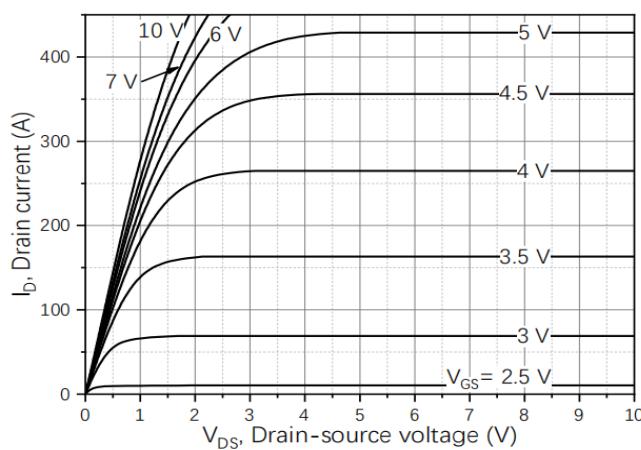


Figure1. Output Characteristics

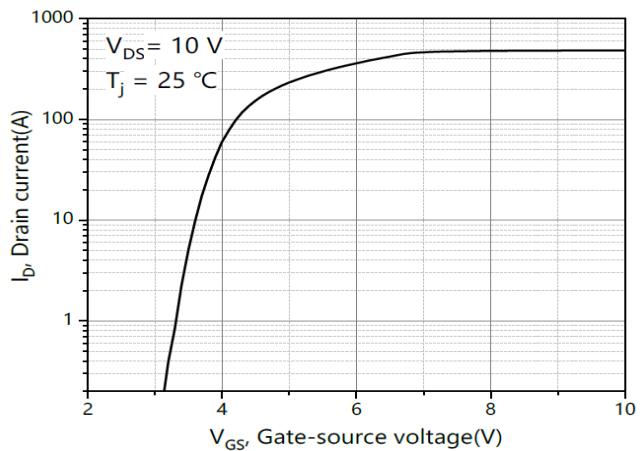


Figure2. Transfer Characteristics

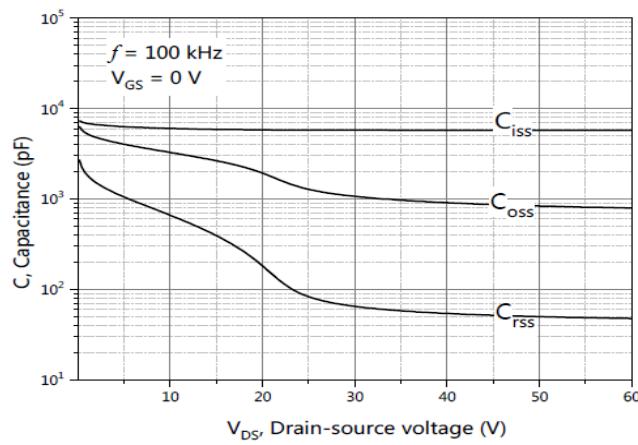


Figure3. Capacitance Characteristics

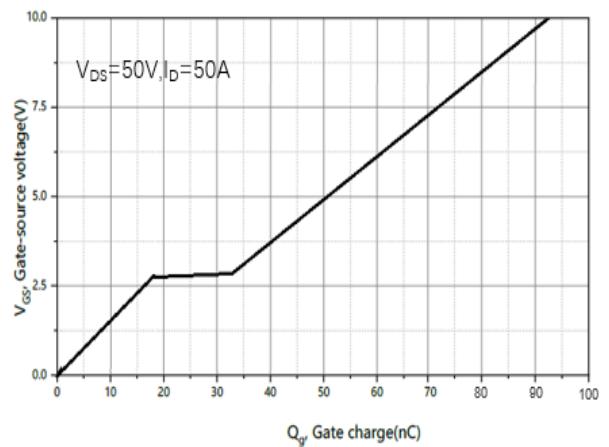


Figure4. Gate Charge

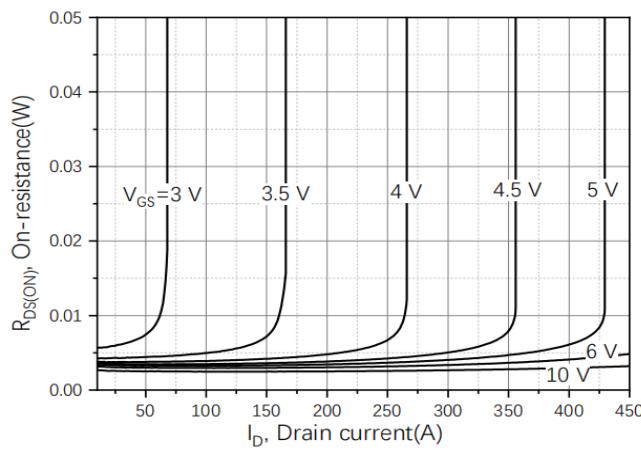


Figure5. Drain-Source on Resistance

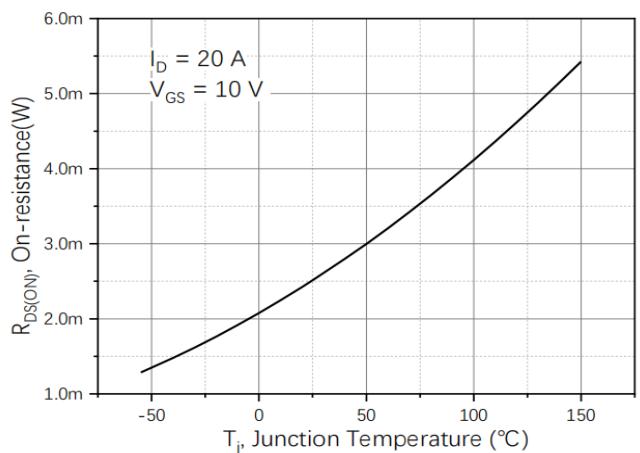


Figure6. Drain-Source on Resistance

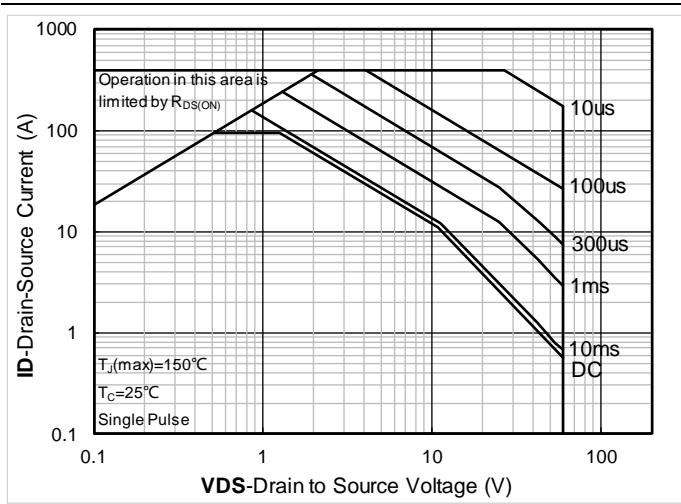


Figure 7. Safe Operation Area

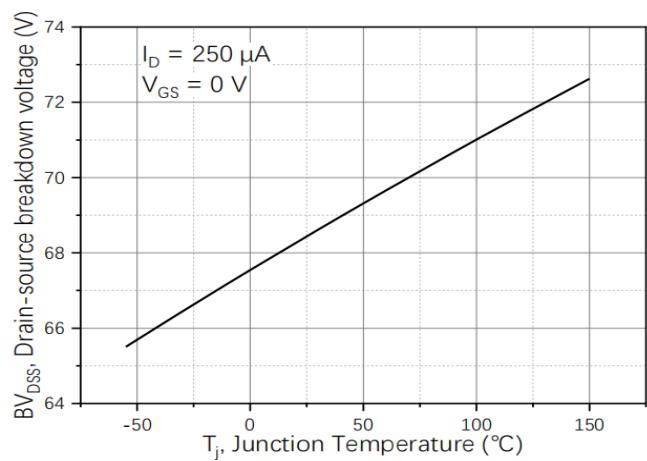


Figure 8. Drain-source breakdown voltage

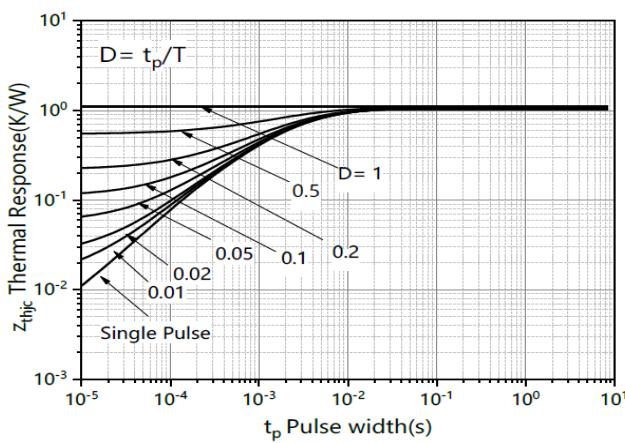


Figure 9. Transient thermal impedance

■ Test circuits and waveforms

Figure A: Gate Charge Test Circuit & Waveforms

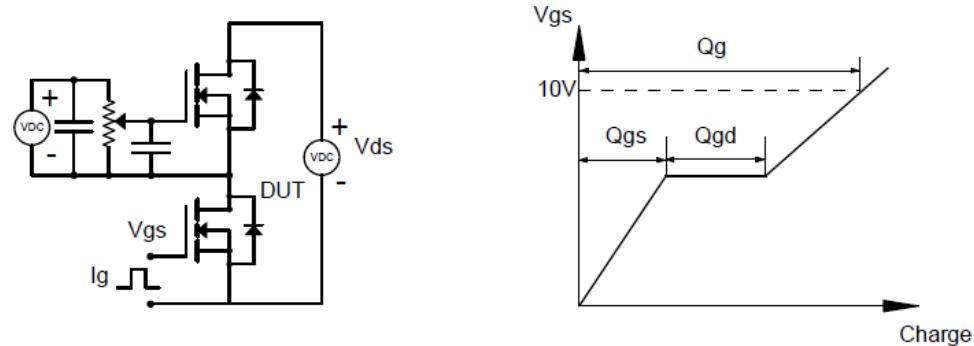


Figure B: Resistive Switching Test Circuit & Waveforms

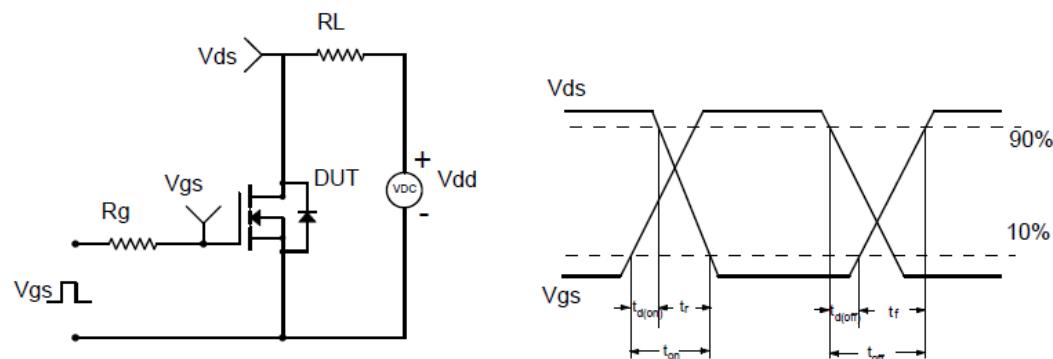


Figure C: Unclamped Inductive Switching (UIS) Test

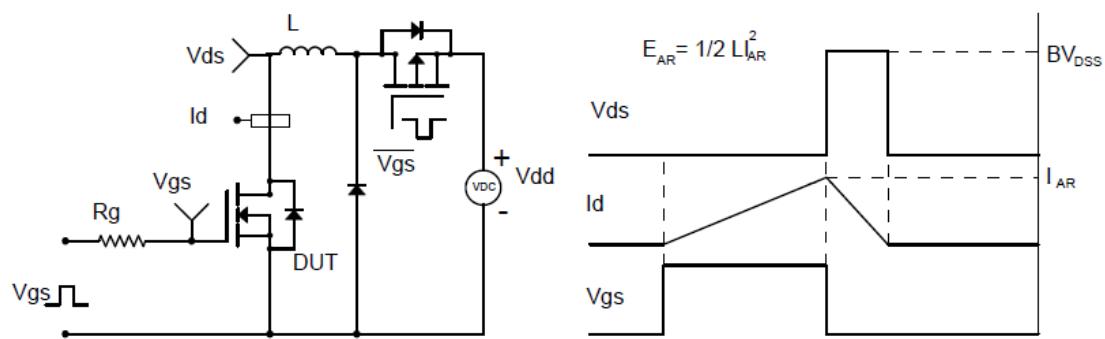
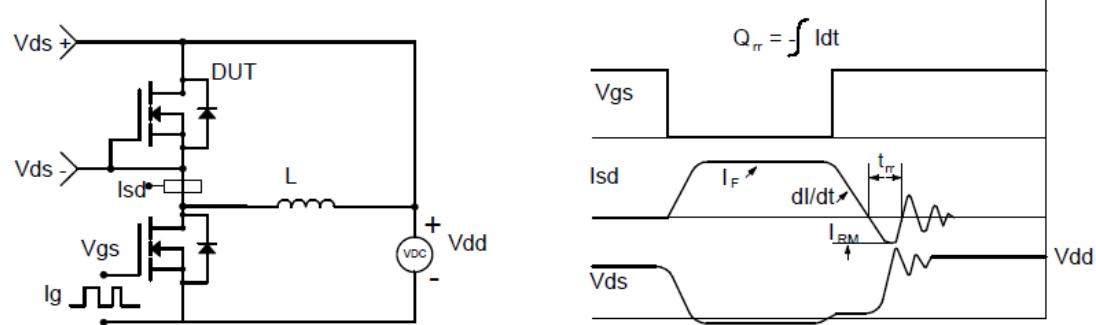
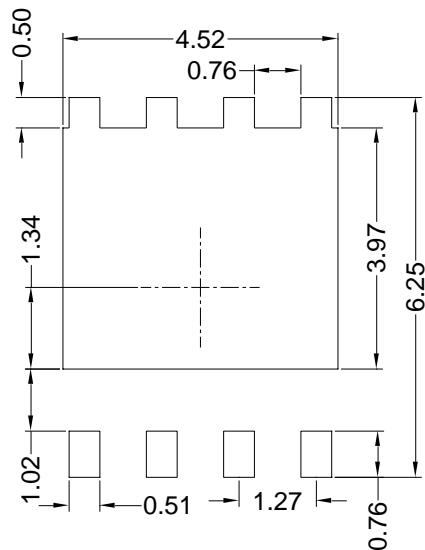
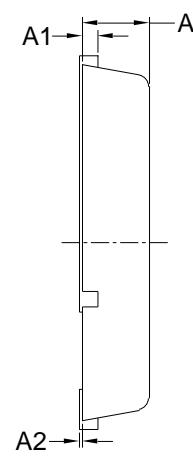
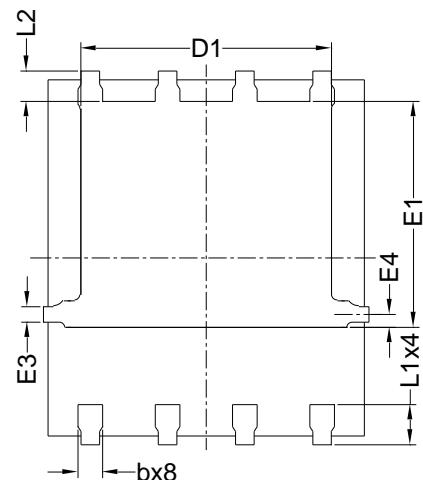
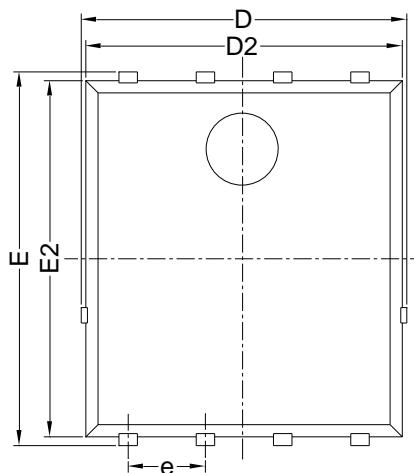


Figure D: Diode Recovery Test Circuit & Waveforms



■ PDFN5060-8L-B-1.1MM Package Information



SYMBOL	MILLIMETER		
	MIN	NOM	MAX
D	5.15	5.35	5.55
E	5.95	6.15	6.35
A	1.00	1.10	1.20
A1	0.254 BSC		
A2			0.10
D1	3.92	4.12	4.32
E1	3.52	3.72	3.92
D2	5.00	5.20	5.40
E2	5.66	5.86	6.06
E3	0.254 REF		
E4	0.21 REF		
L1	0.56	0.66	0.76
L2	0.50 BSC		
b	0.31	0.41	0.51
e	1.27 BSC		

Note:

1. Controlling dimension:in millimeters.
2. General tolerance: $\pm 0.10\text{mm}$.
3. The pad layout is for reference purposes only.

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